

**Amendments to the Specification:**

Please amend the paragraph beginning at page 21, line 18, of the specification as follows:

When the depth profiles of media samples utilized for developing the graphs of FIGS. 3 (A) and 3 (B) were analyzed by Time-of-Flight/Secondary Ion Mass Spectroscopy (~~TEOS/SIMS~~) (TOF/SIMS), the presence of chromium and cobalt oxides ( $\text{CrO}_x$  and  $\text{CoO}_x$ ) was detected between the carbon (C)-based protective overcoat layers and the recording layers when the %  $\text{O}_2$  content of the  $\text{O}_2$ /inert carrier gas mixture was greater than about 0.1 %. The amount of such chromium and cobalt oxides formed when the %  $\text{O}_2$  content was less than about 0.1 % was below the detection limit of the ~~TEOS/SIMS~~ TOF/SIMS technique. Therefore, depending upon the design of the media and the fabrication tool (e.g., post-treatment chamber), and selection of the analysis technique, oxide species formed as a result of the inventive *in situ* post-deposition oxygen treatment may not be detectable.